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	į		U.S. PATENT DOC	UMENTS			
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nitial* No.	Office ³	Number ⁴	Kind Code ⁵ (If known)	of Cited Document	Publication of Cited Document MM-DD- YYYY	Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	Translation ²
W		Shelley Higgins, Oracle Corporation, "Oracle9i, XML Database Developer's Guide – Oracle XML DB," Release 2 (9.2), October 2002, Part No. A96620-02, pp. 1-1,044 (text provided on CD-ROM).	

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Examiner		N //		Date Considered	while
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¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard S.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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(1	OIF	P IN AN APPLICATION (PTO-1449) U.S. Patent Document Number Kind Code ² (If known)		U.S. PATENT DOCU Name of Patentee of Cited Do	or Applicant		Lines, When Relevant Passages o Relevant Figu	re or
M		2003/0140308	A1	Murthy	et al.	07-24-2003	Appear	
Exam. Initial*	Cite No. ¹				CUMENTS ntee or Applicant Document	Date of Publication of Cited Document MM-DD- YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	L ₆

Date Considered

4/10/06

Examiner

Signature

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard S.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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Substitute (use	for Form	1449A/PTO (Modified)	Attorney Docket No.: 50277-2235	1	Application N 10/648,600	Vumber:
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<u> </u>			August 25, 2003		***************************************	
ļ	TR.	OTHER ART - NO PATEN'	T LITERATURE DOCU	JMENTS		
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LE item (book, magazine, journal, serial, sympos publisher, city an		e(s), volume-issu		Translation ²
M		Ipedo, Inc., "Ipedo XML Database 002306148, 12 pages.	3.1: Developer's Guid	de," 2001, XI) <u>.</u>	
por		Chris Parkerson, "Ipedo XML Data XP-002306149, pp. 1-2.	base 3.1 Now Availal	ble," July 22,	2002,	
M		Can Türker, "Schema Evolution in Relational DBMS," 9 th International Languages for Data and Obejcts Fo XP-002306150, pp. 1-32.	l Workshop on Found mlado/Demm 2000, S	lations of Mo September 18	dels and , 2000,	
dy		Hong Su et al., "XEM: XML Evolu 002306151, pp. 1-32.	tion Management," Ja	anuary 2002,	XP-	
por		Yuan Wang et al., "X-Diff: An Effe Documents," Proceedings of the 19 Engineering (ICDE'03), 2003, IEE	th International Confe			
W		Awais Rashid, "A Framework for C Oriented Databases," Proceedings of Engineering and Applications Symp	of the Seventh Interna	tional Databa	se	
for		Xue Li, "A Survey of Schema Evol IEEE, pp. 362-371.	ution in Object-Orien	ted Database	s," 1999,	
sp		International Search Authority, "No Search Report and the Written Opin the Declaration," December 8, 2004 PCT/US2004/027464, 14 pages.	nion of the Internation I, International Applic	al Search Au		
M	<u> </u>	"Current Claims of PCT/US2004/02	27464," pp. 1-7.			
Examiner		1. 1/2		Date Considered	1 4/10	7

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

ATTY. DOCKET NO.
50277-2235

APPLICANT:
Namit Jain et al.

FILING DATE: GROUP: August 25, 2003 2161 2165

Exam. Initial*	Cite No.	U.S. Patent Doo	ument	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM/YYYY	Classification
		Number	(If known)			
M		5,295,261		Simonetti	3/1994	395/600
1		5,467,471		Bader	11/1995	395/600
M		5,724,577		Exley et al.	3/1998	395/611
~		5,734,887		Kingberg et al.	3/1998	395/604
m		5,974,407		Sacks	10/1999	707/2
Mm		6,571,231	B2	Sedlar	5/2003	707/1
w		6,718,322	B1	Brye	4/2004	707/3
m		6,754,661	B1	Hallin et al.	6/2004	707/100

				FC	REIGN PATENT DOCUMENTS			
Exam. Initial*	Cite No. ¹	Office ³	oreign Patent Number ⁴	Document Kind Code ⁵ (If kńown)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶

		OTHER ART - NO PATENT LITERATURE DOCUMENTS		
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Examiner		Date Considered	11111
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INFORMATION DISCLOSURE CITATION O V P N IN AN APPLICATION

(PTO-1449)

ATTY. DOCKET NO. 50277-2235	SERIAL NO. 10/648,600
APPLICANT: Namit Jain et al.	
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August 25, 2003

U.S. PATENT DOCUMENTS U.S. Patent Document Exam. Cite Name of Patentee or Applicant Date of Publication of Pages, Columns, Initial* No. of Cited Document Cited Document Lines, Where Number Kind Code² MM-DD-YYYY Relevant (If known) Passages or Relevant Figures Appear 2003/0004937 Salmenkaita et al. A1 01-02-2003 2004/0043758 A1 Sorvari et al. 03-04-2004 2004/0176958 A1 Salmenkaita et al. 09-09-2004 2004/0225680 A1 Cameron et al. 11-11-2004 2005/0050092 A₁ Jain et al. 03-03-2005

			FORE	IGN PATENT DOCUMENTS			
Exam. Cite	F	Foreign Patent Document		Name of Patentee or Applicant	Date of	Pages,	т
Initial* No.	Office ³	Number ⁴	Kind Code ⁵ (If known)	of Cited Document	Publication of Cited Document MM-DD-YYYY	Columns, Lines, Where Relevant Passages or Relevant Figures Appear	,

·		OTHER ART – NO PATENT LITERATURE DOCUMENTS	
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W		Chen, Ruey-Shun et al., "Developing an XML framework for metadata system", Trinity College Dublin, Proc. of the 1 st Inter. Sympo. on Information and Communication, pages 267-272.	
W		Manolescu, Dragos, Review of "Metadata solutions: using metamodels, repositories, XML, and enterprise portals to generate information on demand by Adrienne Tannebaum", 3/2003, ACM Press, Volume 28, Issue 2, page 38.	

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Examiner			$\overline{}$		10/		Date Considered	10/11
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Examiner

Signature

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard S.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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INFORMATION DISCLOSURE CITATION OF E IN AN APPLICATION (PTO-1449)									ATTY. DOCK 50277-2235	SERIAL NO. 10/648,600				
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Examiner

Signature

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